

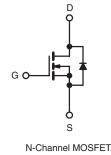
## P14NF10FP-VB Datasheet N-Channel 100-V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	100					
R <sub>DS(on)</sub> (Ω)	V <sub>GS</sub> = 10 V	0.086				
Q <sub>g</sub> (Max.) (nC)	72					
Q <sub>gs</sub> (nC)	11					
Q <sub>gd</sub> (nC)	32					
Configuration	Single					

#### **FEATURES**

- Isolated Package
- High Voltage Isolation = 2.5 kV<sub>RMS</sub> (t = 60 s; f = 60 Hz)
- Sink to Lead Creepage Distance = 4.8 mm
- 175 °C Operating Temperature
- Dynamic dV/dt Rating
- Low Thermal Resistance
- Lead (Pb)-free Available





PARAMETER			SYMBOL	LIMIT	UNIT		
Drain-Source Voltage			V <sub>DS</sub>	100	- V		
Gate-Source Voltage			V <sub>GS</sub>	± 20			
Continuous Drain Current	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C	I_	18			
	VGS at 10 V	T <sub>C</sub> = 100 °C	ID	12	A		
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	68	1		
Linear Derating Factor				0.32	W/°C		
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	720	mJ		
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	I <sub>AR</sub> 17			
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	4.8	mJ		
Maximum Power Dissipation	T <sub>C</sub> =	25 °C	PD	48	W		
Peak Diode Recovery dV/dt <sup>c</sup>			dV/dt	5.5	V/ns		
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 175	°C		
Soldering Recommendations (Peak Temperature)	for	10 s		300 <sup>d</sup>			
Mounting Torque	6 22 or 1	6-32 or M3 screw		10	lbf ⋅ in		
	6-32 OF M3 SCIEW		F	1.1	N ⋅ m		

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b.  $V_{DD} = 25 \text{ V}$ , starting  $T_J = 25 \text{ °C}$ , L = 3.7 mH,  $R_G = 25 \Omega$ ,  $I_{AS} = 17 \text{ A}$  (see fig. 12). c.  $I_{SD} \le 17 \text{ A}$ , dl/dt  $\le 200 \text{ A}/\mu\text{s}$ ,  $V_{DD} \le V_{DS}$ ,  $T_J \le 175 \text{ °C}$ .

d. 1.6 mm from case.

THERMAL RESISTANCE RA	TINGS							
PARAMETER	SYMBOL	TYP.		MAX.		UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	- 65			°C 111		
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	- 3.1				°C/W		
<b>SPECIFICATIONS</b> $T_J = 25 \ ^{\circ}C$ ,	unless otherw	vise noted			-		-	-
PARAMETER	SYMBOL	TES	T CONDITI	ONS	MIN.	TYP.	MAX.	UNIT
Static								
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> =	= 0 V, I <sub>D</sub> = 2	50 μΑ	100	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	I <sub>D</sub> = 1 mA	-	0.13	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$			1.0	-	3.0	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 20 \text{ V}$			-	-	± 100	nA
Zaro Gata Voltago Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =	$V_{DS} = 100 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$		-	-	25	
Zero Gate Voltage Drain Current		$V_{DS} = 80 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 150 ^{\circ}\text{C}$			-	-	250	μΑ
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	۱ <sub>D</sub>	= 10 A <sup>b</sup>	-	0.086	-	Ω
Forward Transconductance	<b>g</b> <sub>fs</sub>	V <sub>DS</sub> =	= 50 V, I <sub>D</sub> =	10 A <sup>b</sup>	9.1	-	-	S
Dynamic								
Input Capacitance	C <sub>iss</sub>		$V_{GS} = 0 V_{,}$		-	1700	-	
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 25 V, f = 1.0 MHz, see fig. 5		-	560	-	рF	
Reverse Transfer Capacitance	C <sub>rss</sub>			-	120	-		
Drain to Sink Capacitance	С			-	12	-		
Total Gate Charge	Qg			-	-	72		
Gate-Source Charge	Q <sub>gs</sub>	$V_{GS} = 10 V$		A, V <sub>DS</sub> = 80 V, ig. 6 and 13 <sup>b</sup>	-	-	11	nC
Gate-Drain Charge	Q <sub>gd</sub>				-	-	32	
Turn-On Delay Time	t <sub>d(on)</sub>				-	11	-	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 50 V, $I_D$ = 17 A, $R_G$ = 9.1 $\Omega$ , $R_D$ = 2.9 $\Omega$ , see fig. 10 <sup>b</sup>		-	44	-	ns	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	53	-		
Fall Time	t <sub>f</sub>			-	43	-		
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nH	
Internal Source Inductance	L <sub>S</sub>			-	7.5	-		
Drain-Source Body Diode Characteristic	s	•						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	17	A	
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	68		
Body Diode Voltage	$V_{SD}$	$T_J=25~^{\circ}C,~I_S=17~A,~V_{GS}=0~V^b$		-	-	2.5	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>	$T_J = 25 \text{ °C}, I_F = 17 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}^b$		-	180	360	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	1.3	2.6	μC	
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S$ and $L_D$ )						

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width  $\leq$  300  $\mu s;$  duty cycle  $\leq$  2 %.





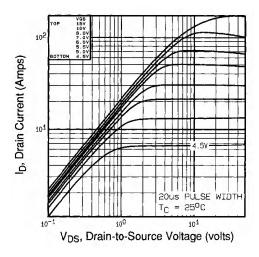


Fig. 1 - Typical Output Characteristics, T<sub>C</sub> = 25 °C

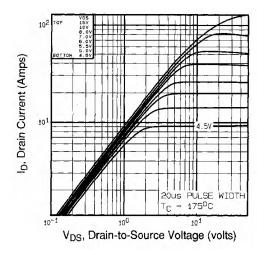


Fig. 2 - Typical Output Characteristics,  $T_C = 175$  °C

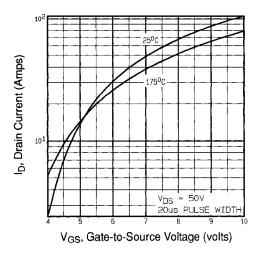


Fig. 3 - Typical Transfer Characteristics

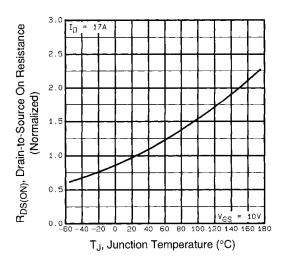


Fig. 4 - Normalized On-Resistance vs. Temperature

### P14NF10FP-VB

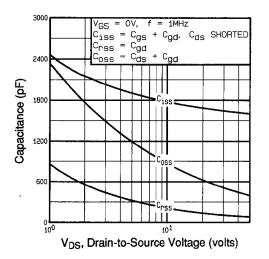
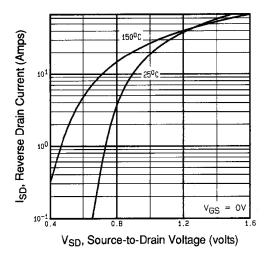


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



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Fig. 7 - Typical Source-Drain Diode Forward Voltage

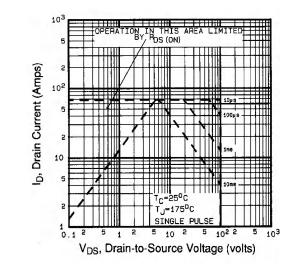


Fig. 8 - Maximum Safe Operating Area

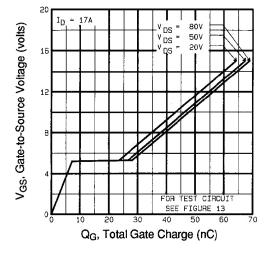


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

### P14NF10FP-VB



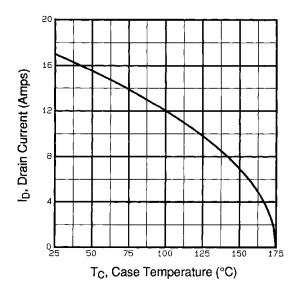


Fig. 9 - Maximum Drain Current vs. Case Temperature

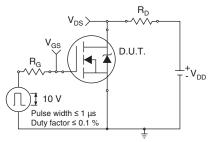


Fig. 10a - Switching Time Test Circuit

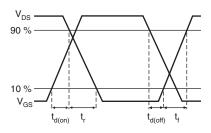


Fig. 10b - Switching Time Waveforms

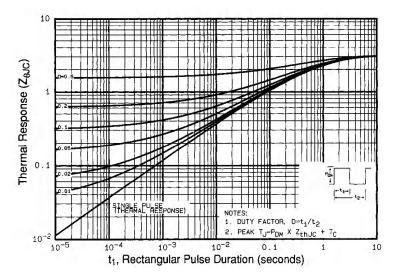


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

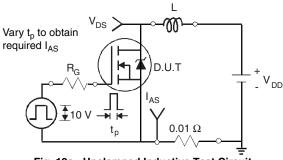


Fig. 12a - Unclamped Inductive Test Circuit

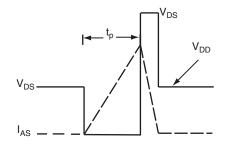


Fig. 12b - Unclamped Inductive Waveforms



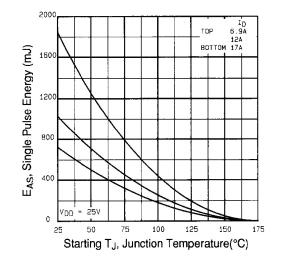


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

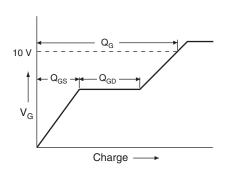
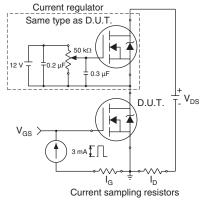
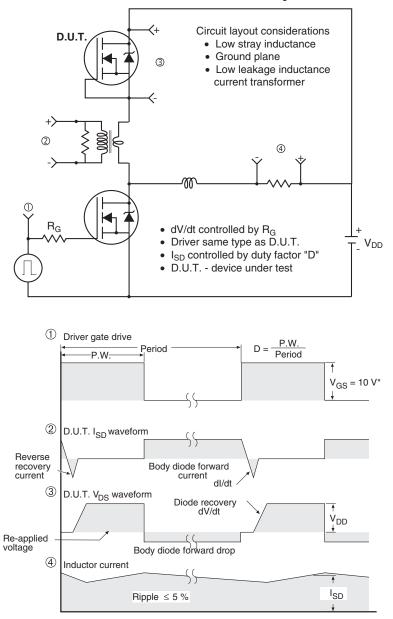


Fig. 13a - Basic Gate Charge Waveform









Peak Diode Recovery dV/dt Test Circuit

\*  $V_{GS} = 5 V$  for logic level devices

Fig.14 - For N-Channel



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